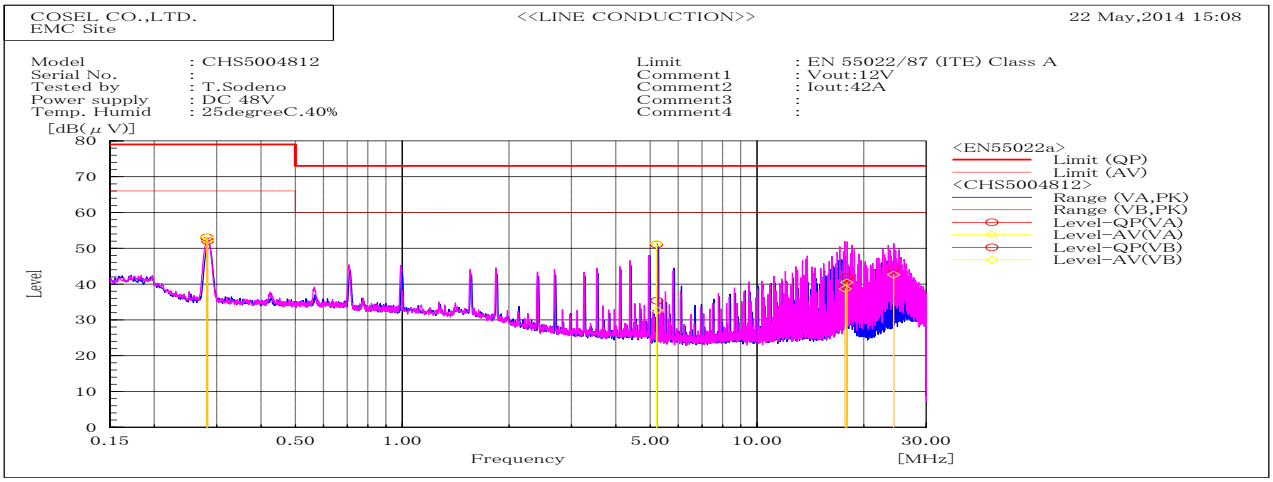
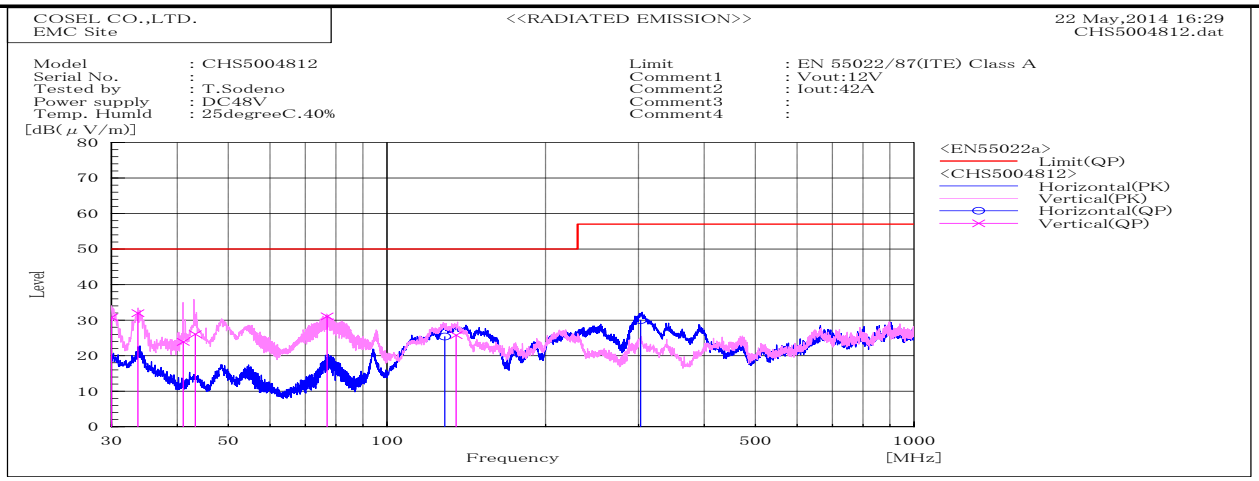
参考資料

COSEL

DATA SHEET		Date	22-Jun-16
Model	CHS5004812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sodeno



Frequency	Harm	Line Phas	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.28253		VA	32	32	20.1	52.1	52.1	79	66	26.9	13.9	Pass	
0.28156		VB	32.9	33	20.1	53	53.1	79	66	26	12.9	Pass	
5.21407		VB	30.6	30.9	20.4	51	51	73	60	22	22	Pass	
5.22275		VA	15	12.3	20.4	35.4	32.7	73	60	37.6	27.3	Pass	
17.74935		VA	18.5	17.7	20.9	39.4	38.6	73	60	33.6	21.4	Pass	
17.92305		VB	21	19.5	20.9	41.9	40.4	73	60	31.1	19.6	Pass	
24.2583		VB	23.4	21.7	20.9	44.3	42.6	73	60	28.7	17.4	Pass	



Frequency MHz	Polarization	Stability	Reading dB(uV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP		QP	QP	QP				
30.009	V	Stable	44.3	-13.5	30.8	50	19.2	Pass	100	15	
33.682	V	Stable	46.5	-14.5	32	50	18	Pass	100	270	
41.047	V	Stable	39.5	-15.6	23.9	50	26.1	Pass	100	52	
43.267	V	Stable	43.5	-17.5	26	50	24	Pass	100	334	
77.001	V	Stable	51.4	-20.3	31.1	50	18.9	Pass	100	297	
128.658	H	Stable	45.2	-19.8	25.4	50	24.6	Pass	159	203	
135.239	V	Stable	43.3	-17.5	25.8	50	24.2	Pass	159	243	
302.765	H	Stable	47.6	-17.6	30	57	27	Pass	100	309	

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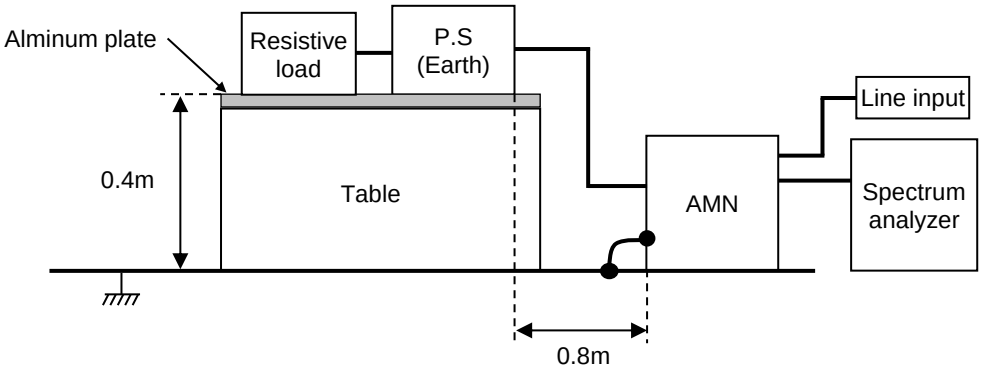
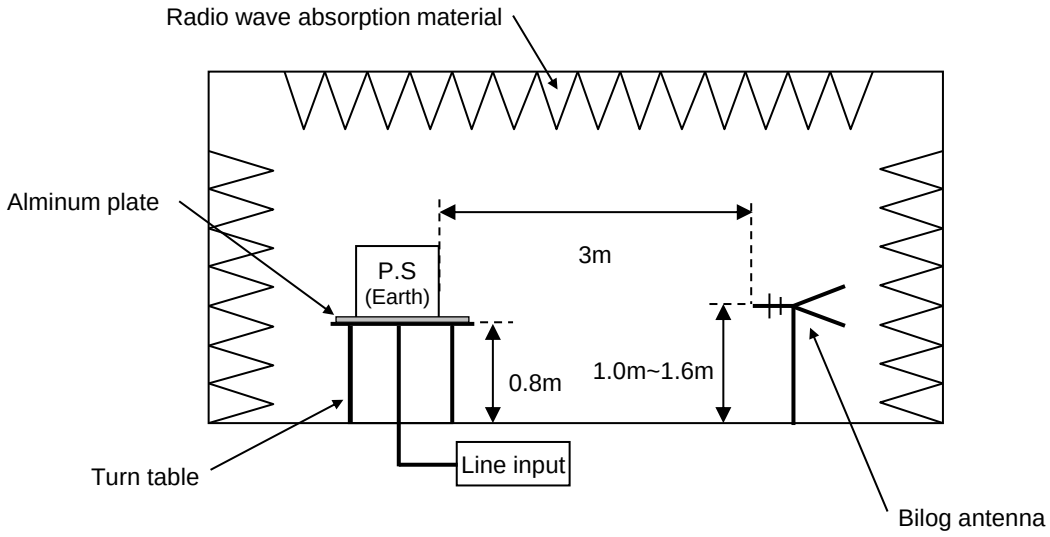
DATA SHEET		Date	22-Jun-16
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sodeno

1. Line conduction



2. Radiated emission

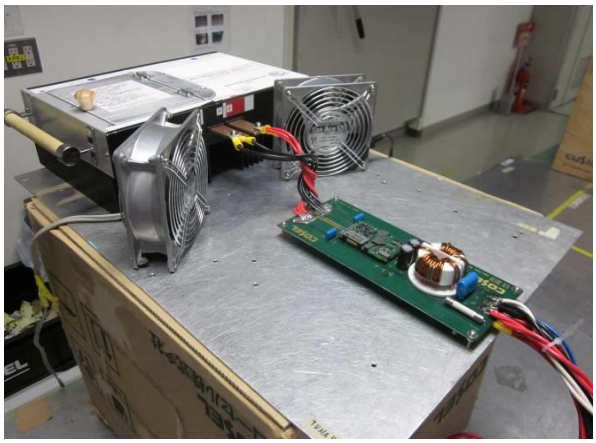


COSEL

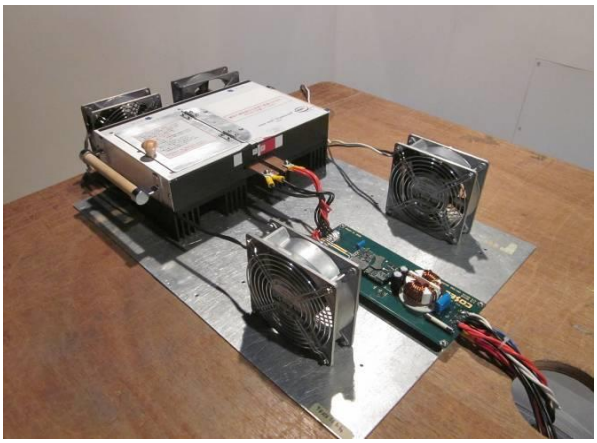
Test : EMI
Model Name : CHS5004812

○ Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○ Testing circuitry

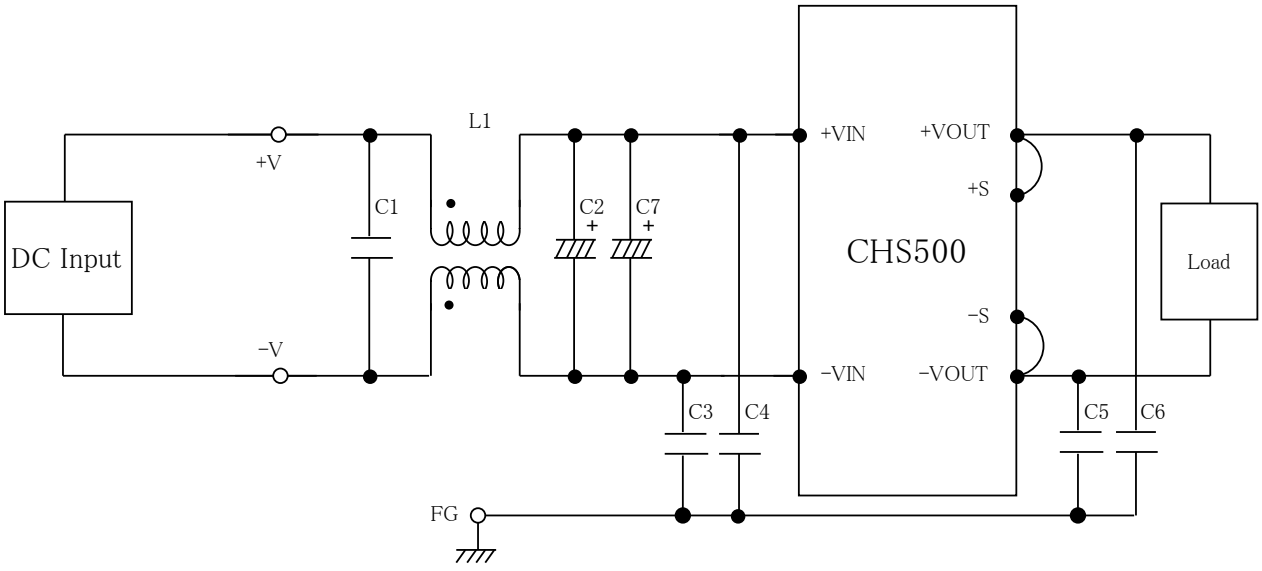


Fig.1 Testing circuitry

L1 : 1mH SC-20-10JH (TOKIN)
C1 : 250V 2.2μF FPD22E225J4 (NITSUKO)
C2,C7 : 100V 100μF PWseries (nichicon)
C3,C4 : 630V 0.068μF FPD22J683J4 (NITSUKO)
C5,C6 : 630V 0.033μF FPD22J333J4 (NITSUKO)